


<p style="text-align: center;"><b>Search Notes</b></p> 	<p><b>Application/Control No.</b></p> <p>10586357</p>	<p><b>Applicant(s)/Patent Under Reexamination</b></p> <p>FUKUI ET AL.</p>
	<p><b>Examiner</b></p> <p>PING Y HSIEH</p>	<p><b>Art Unit</b></p> <p>2618</p>

SEARCHED			
Class	Subclass	Date	Examiner
455	41.1, 522, 69, 67.11, 126, 68, 127.1, 572, 574	2/27/10	PH
340	567, 541, 555, 565	2/27/10	PH
327	142, 143, 198, 530, 545, 546, 108, 544, 185, 50	2/27/10	PH
250	338.3, 338.1, 336.1, 338.2, 339.14, 342, 221	2/27/10	PH

SEARCH NOTES		
Search Notes	Date	Examiner
Text search in EAST (see search history)	2/27/10	PH
PLUS search	2/28/08	PH
Consulted with Yuwen Pan	2/4/09	PH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
455	see interference search in EAST	2/27/10	PH

/P. Y. H./  
Examiner, Art Unit 2618